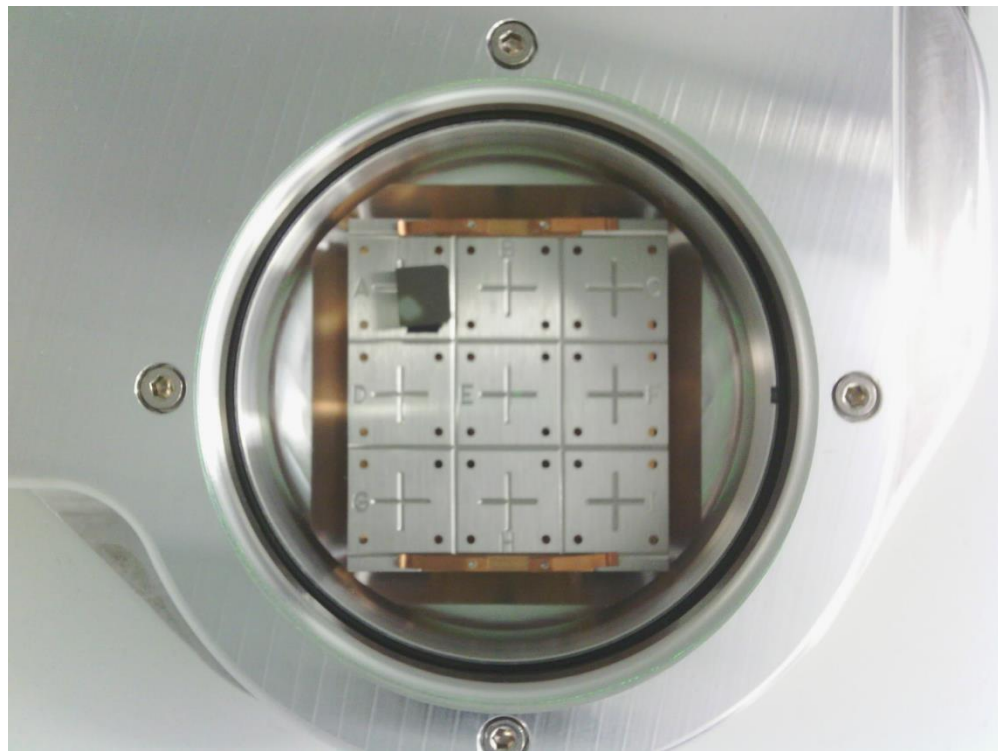
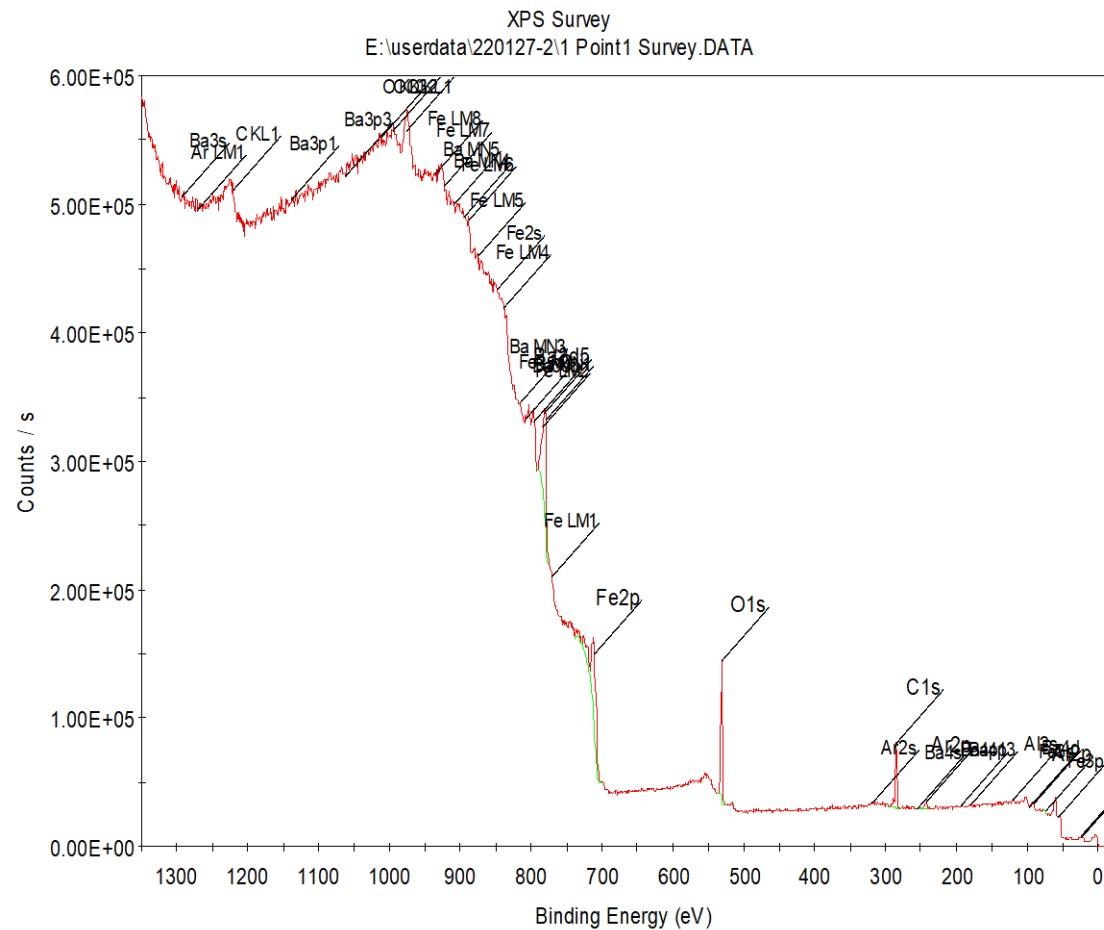


XPS分析事例-3

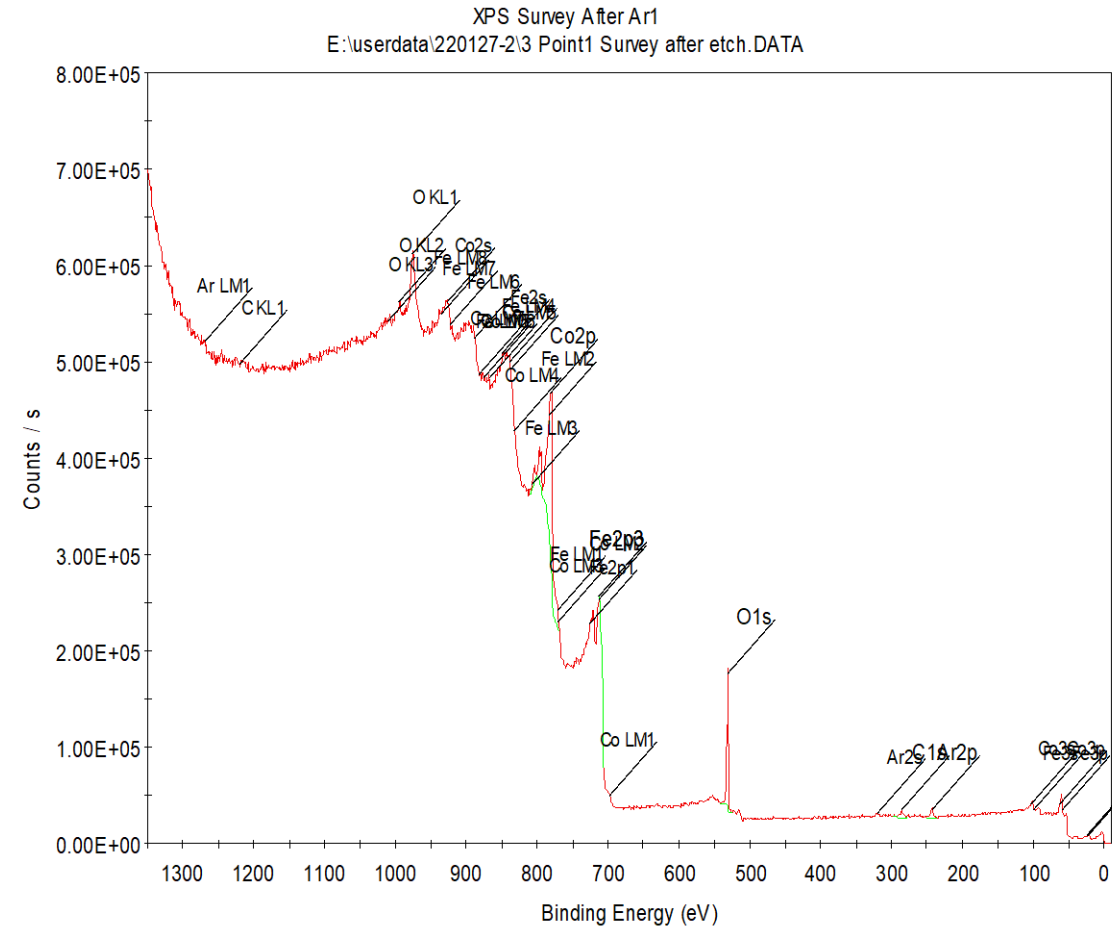
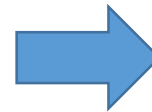
単Arエッチングによる深さ方向分析



Arエッチング前後のサーベイスキャン結果 1

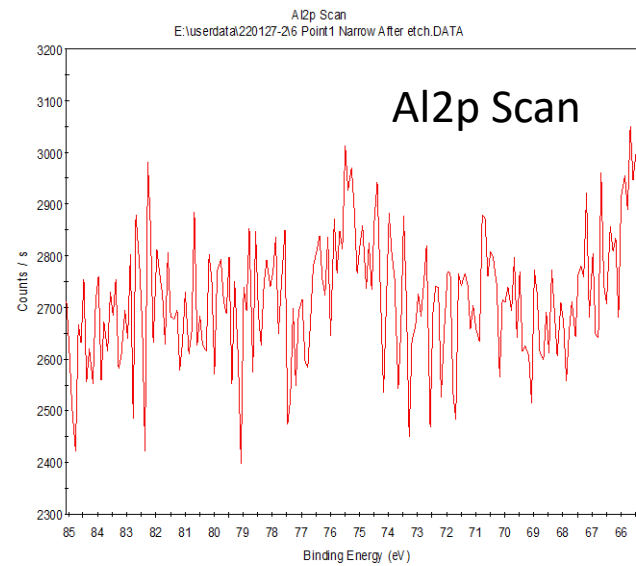
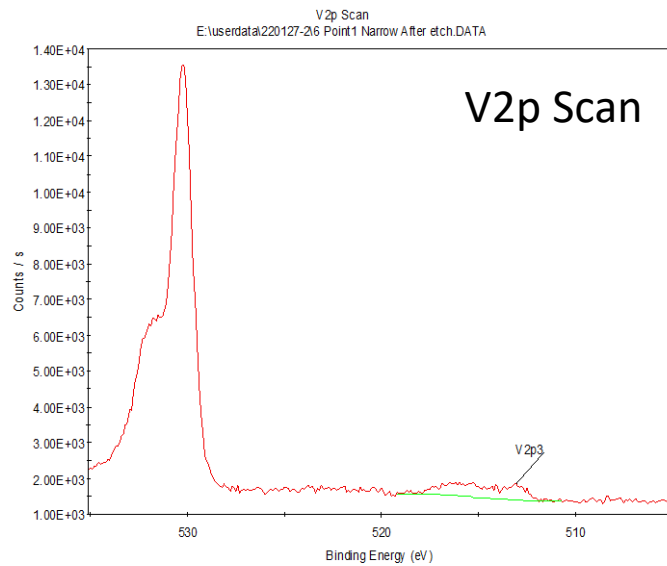
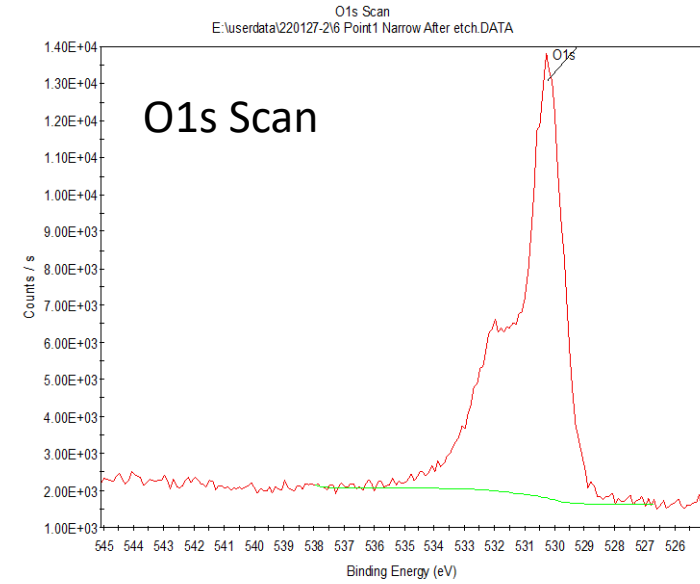
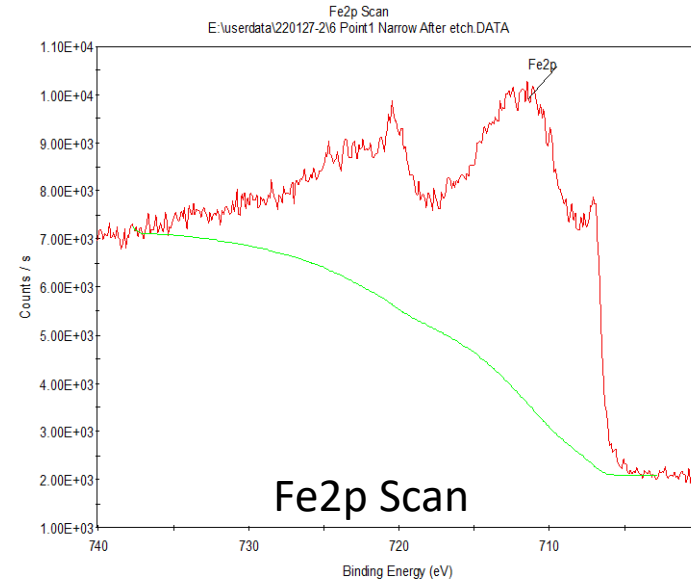
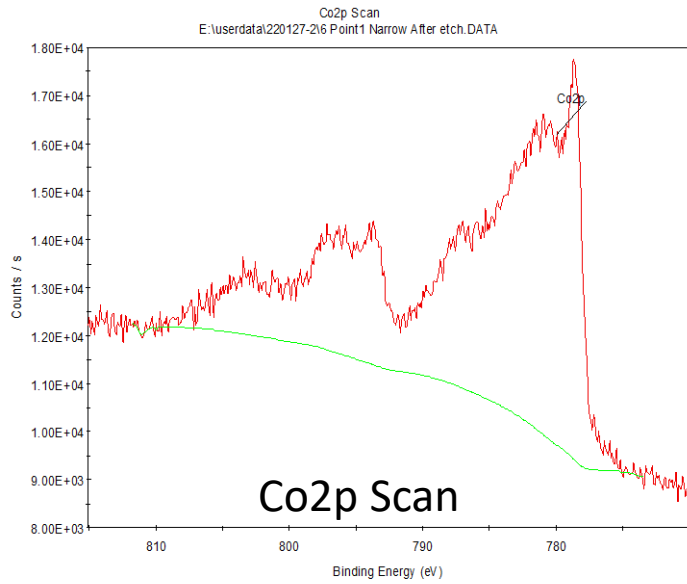


Arエッチング前



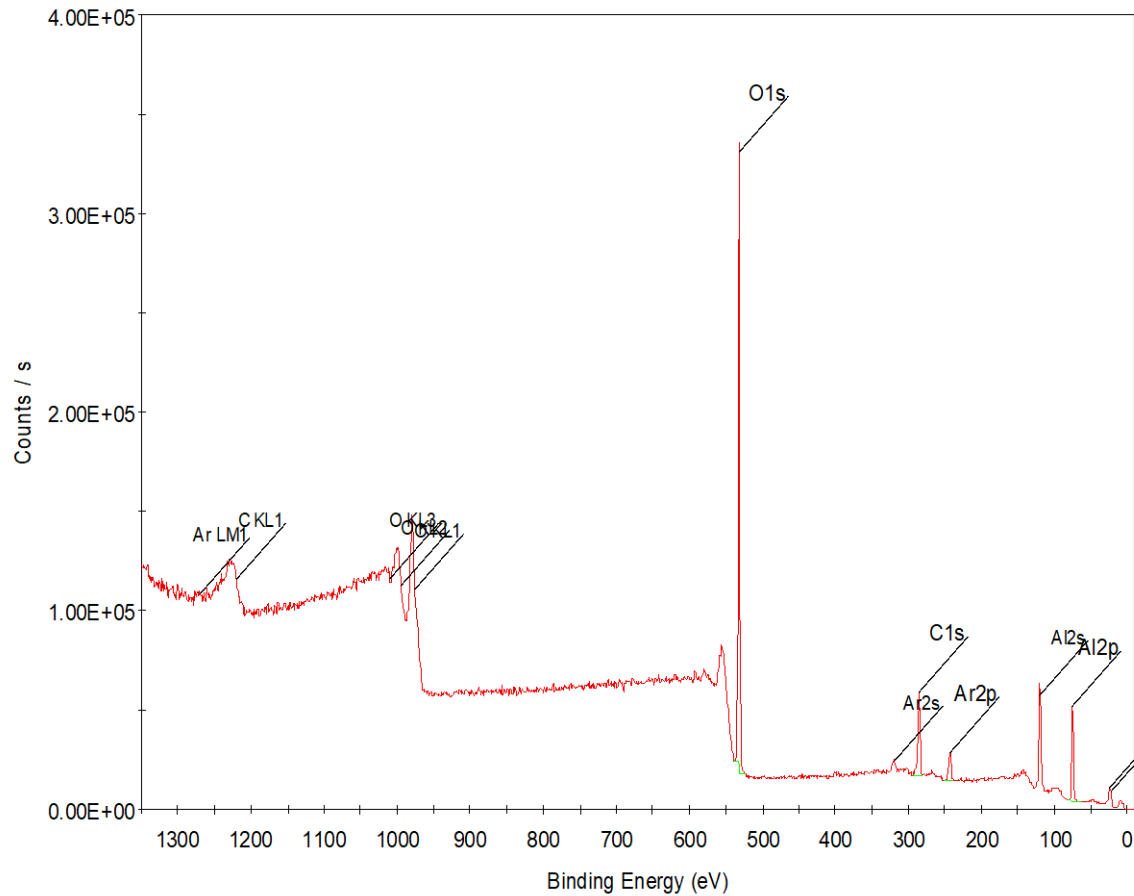
Arエッチング後

Arエッチング後のナロースキャン結果 1

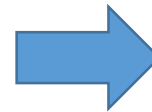


Arエッチング前後のサーベイスキャン結果 2

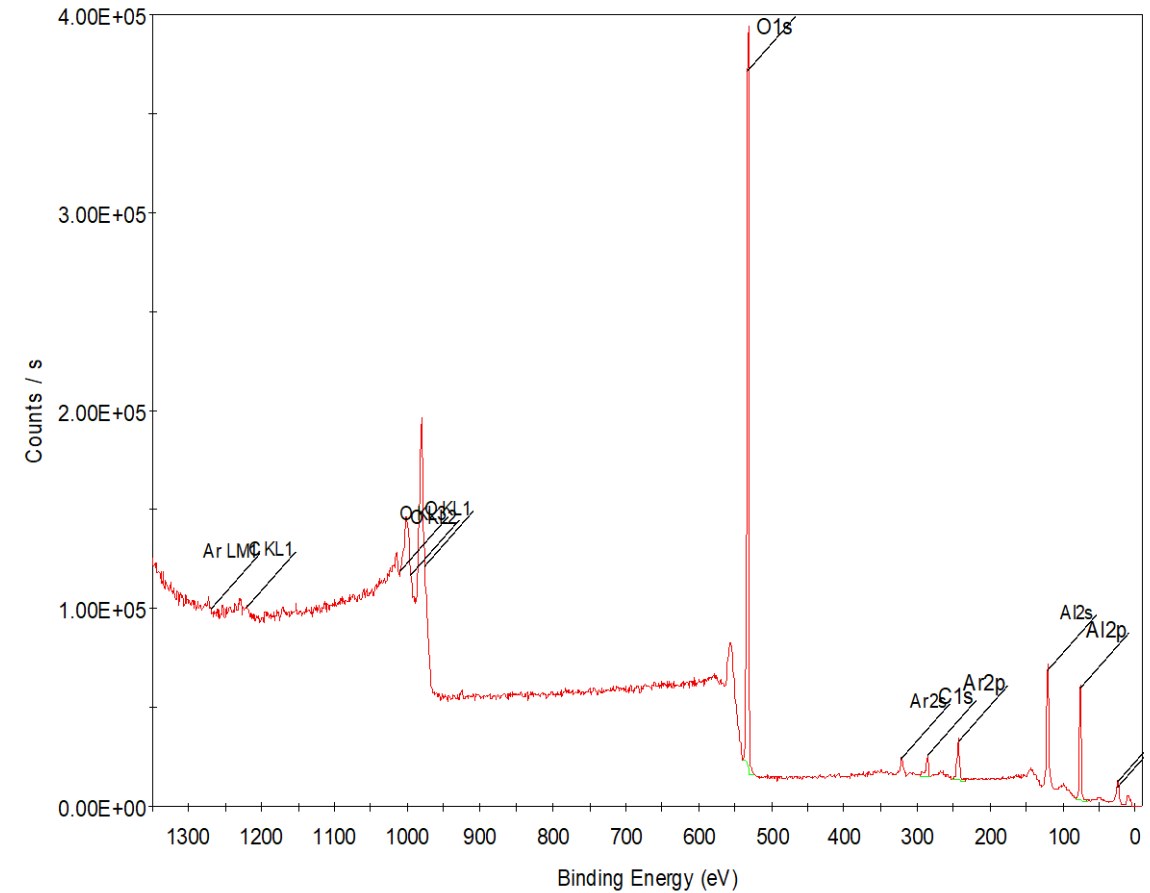
XPS Survey
E:\userdata\220127-2\2 Point5 Survey.DATA



Arエッチング前



XPS Survey After Ar1
E:\userdata\220127-2\4 point5 Survey after etch.DATA



Arエッチング後

Arエッチング後のナロースキャン結果 2

